JETIR.ORG

## ISSN: 2349-5162 | ESTD Year: 2014 | Monthly Issue



## JOURNAL OF EMERGING TECHNOLOGIES AND INNOVATIVE RESEARCH (JETIR)

An International Scholarly Open Access, Peer-reviewed, Refereed Journal

Ref No: JETIR / Vol 10 / Issue 1 / 346

**Confirmation Letter** 

To,

Irfan Ayoub

Published in : Volume 10 | Issue 1 | 2023-01-23



Subject: Publication of paper at International Journal of Emerging Technologies and Innovative Research.

Dear Author,

With Greetings we are informing you that your paper has been successfully published in the International Journal of Emerging Technologies and Innovative Research (ISSN: 2349-5162). Following are the details regarding the published paper.

: An International Scholarly Open Access Journal, Peer-Reviewed, Refereed About JETIR

> Journal Impact Factor Calculate by Google Scholar and Semantic Scholar AI-Powered Research Tool, Multidisciplinary, Monthly, Multilanguage Journal Indexing in All Major Database & Metadata, Citation Generator, Impact Factor:

7.95, ISSN: 2349-5162

UGC Approval: UGC and ISSN Approved - UGC Approved Journal No: 63975 | Link:

https://www.ugc.ac.in/journallist/subjectwisejurnallist.aspx?tid=MjM0OTUxNjI

=&&did=U2VhcmNoIGJ5IElTU04=

Registration ID: JETIR 506949 Paper ID : JETIR2301346

Title of Paper : Apple Leaf Diseases Identification Using Deep Learning

Impact Factor : 7.95 (Calculate by Google Scholar)

DOI

Published in : Volume 10 | Issue 1 | 2023-01-23

Publication Date: 2023-01-23 Page No : d385-d390

Published URL: http://www.jetir.org/view?paper=JETIR2301346 : Irfan Ayoub, Dr. Bhawna Sharma, Dr. Simmi Dutta Authors

Thank you very much for publishing your article in JETIR. We would appreciate if you continue your support and keep sharing your knowledge by writing for our journal JETIR.

















International Journal of Emerging Technologies and Innovative Research (ISSN: 2349-5162)

www.jetir.org | editor@jetir.org | Impact Factor: 7.95 (Calculate by Google Scholar)

An International Scholarly Open Access Journal, Peer-Reviewed, Refereed Journal